

# CLASS V, 13 BIT, 250 MSPS ANALOG-TO-DIGITAL CONVERTER

Check for Samples: ADS5444-SP

## **FEATURES**

- 13 Bit Resolution
- 250 MSPS Sample Rate
- SNR = 67.6 dBc at 230 MHz IF and 250 MSPS
- SFDR = 74.0 dBc at 230 MHz IF and 250 MSPS
- 2.2 V<sub>PP</sub> Differential Input Voltage
- Fully Buffered Analog Inputs
- 5 V Analog Supply Voltage
- LVDS Compatible Outputs
- Total Power Dissipation: 2 W
- Offset Binary Output Format
- Pin Compatible With the ADS5440
- Military Temperature Range (-55°C to 125°C T<sub>case</sub>)

### **APPLICATIONS**

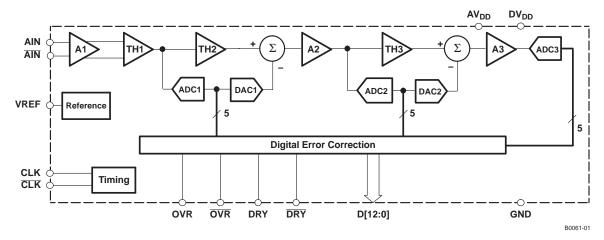
- Test and Measurement
- Software-Defined Radio
- Multichannel Base Station Receivers
- Base Station Tx Digital Predistortion
- Communications Instrumentation
- Engineering Evaluation (/EM) Samples are Available (1)

### RELATED PRODUCTS

- ADS5424 14 Bit, 105 MSPS ADC
- ADS5423 14 Bit, 80 MSPS ADC
- ADS5440 13 Bit, 210 MSPS ADC
- (1) These units are intended for engineering evaluation only. They are processed to a non-compliant flow (e.g. no burn-in, etc.) and are tested to temperature rating of 25°C only. These units are not suitable for qualification, production, radiation testing or flight use. Parts are not warranted for performance on full MIL specified temperature range of -55°C to 125°C or operating life.

## **DESCRIPTION**

The ADS5444 is a 13 bit 250 MSPS analog-to-digital converter (ADC) that operates from a 5 V supply, while providing LVDS-compatible digital outputs from a 3.3 V supply. The ADS5444 input buffer isolates the internal switching of the onboard track and hold (T&H) from disturbing the signal source. An internal reference generator is also provided to further simplify the system design. The ADS5444 has outstanding low noise and linearity over input frequency.



The ADS5444 is available in a 84 pin ceramic nonconductive tie-bar package (HFG). The ADS5444 is built on a state-of-the-art Texas Instruments complementary bipolar process (BiCom3X) and is specified over the full military temperature range (–55°C to 125°C T<sub>case</sub>).



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

## **ABSOLUTE MAXIMUM RATINGS**

over operating temperature range (unless otherwise noted)(1)

		VALUE/UNIT
Supply voltage	AV <sub>DD</sub> to GND	6 V
	DRV <sub>DD</sub> to GND	5 V
Analog input to	GND	-0.3 V to AV <sub>DD</sub> + 0.3 V
Clock input to G	SND	-0.3 V to AV <sub>DD</sub> + 0.3 V
CLK to CLK		±2.5 V
Digital data outp	out to GND	$-0.3 \text{ V to DRV}_{DD} + 0.3 \text{ V}$
$T_C$	Characterized case operating temperature range	−55°C to 125°C
T <sub>J</sub>	Maximum junction temperature	150°C
T <sub>stg</sub>	Storage temperature range	−65°C to 150°C
ESD Human Bo	dy Model (HBM)	2.5 kV

<sup>(1)</sup> Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only and functional operation of the device at these or any other conditions beyond those specified is not implied.

## RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
SUPPLIE	S			•	
$AV_{DD}$	Analog supply voltage	4.75	5	5.25	V
$DRV_DD$	Output driver supply voltage	3	3.3	3.6	V
ANALOG	INPUT				
	Differential input range		2.2		$V_{PP}$
V <sub>CM</sub>	Input common mode		2.4		V
CLOCK I	NPUT				
	ADCLK input sample rate (sine wave)	10		250	MSPS
	Clock amplitude, differential sine wave		3		$V_{PP}$
	Clock duty cycle		50%		
T <sub>C</sub>	Operating case temperature	-55		125	°C



# **ELECTRICAL CHARACTERISTICS**

Typical values at  $T_C = 25$ °C, full temperature range is  $T_{C,MIN} = -55$ °C to  $T_{C,MAX} = 125$ °C, sampling rate = 250 MSPS, 50% clock duty cycle,  $AV_{DD} = 5$  V,  $DRV_{DD} = 3.3$  V, -1 dBFS differential input, and 3 V<sub>PP</sub> differential clock (unless otherwise noted)

PARAMETER		TES	MIN	TYP	MAX	UNIT	
	Resolution				13		Bits
ANALO	G INPUTS						
	Differential input range				2.2		$V_{pp}$
	Differential input resistance (DC)				1		kΩ
	Differential input capacitance				1.5		pF
	Analog input bandwidth				800		MHz
INTERN	AL REFERENCE VOLTAGE						
VREF	Reference voltage			2.38	2.4	2.42	V
DYNAM	IC ACCURACY						
	No missing codes				Assured		
DNL	Differential linearity error	f <sub>IN</sub> = 100 MHz	Full temp range	-0.98	±0.4	2	LSB
INL	Later week Programmer	f <sub>IN</sub> = 100 MHz	$T_C = 25^{\circ}C$ and $T_{C,MAX}$	-2.8		2.8	1.00
	Integral linearity error		$T_C = T_{C,MIN}$	-4.8		4.8	LSB
	Offset error		Full temp range	-0.6		0.6	%FS
	Offset temperature coefficient				0.0005		%FS/°C
	Gain error		Full temp range	-5		5	%FS
	Gain temperature coefficient				-0.02		%FS/°C
POWER	SUPPLY						
I <sub>AVDD</sub>	Analog supply current				340	410	mA
I <sub>DRVDD</sub>	Output buffer supply current	V <sub>IN</sub> = full scale, f <sub>IN</sub> = 170 MHz, F <sub>S</sub> = 250 MSPS			80	100	mA
	Power dissipation				2	2.29	W
DYNAM	IC AC CHARACTERISTICS						
		f <sub>IN</sub> = 10 MHz	T <sub>C</sub> = 25°C	68.0	69.1		
			$T_C = T_{C,MAX}$	66.8			
			$T_C = T_{C,MIN}$	63.2			
		f <sub>IN</sub> = 70 MHz			69.0		
		f <sub>IN</sub> = 100 MHz	T <sub>C</sub> = 25°C	67.3	68.9		
			$T_C = T_{C,MAX}$	66.5			
SNR	Signal-to-noise ratio		$T_C = T_{C,MIN}$	62.1			dBc
		f <sub>IN</sub> = 170 MHz	T <sub>C</sub> = 25°C	66.5	68.4		
			$T_C = T_{C,MAX}$	66.1			
			$T_C = T_{C,MIN}$	60.8			
		f <sub>IN</sub> = 230 MHz			67.6		
		f <sub>IN</sub> = 300 MHz			66.5		
		f <sub>IN</sub> = 400 MHz			65.5		



## **ELECTRICAL CHARACTERISTICS (continued)**

Typical values at  $T_C = 25^{\circ}\text{C}$ , full temperature range is  $T_{C,MIN} = -55^{\circ}\text{C}$  to  $T_{C,MAX} = 125^{\circ}\text{C}$ , sampling rate = 250 MSPS, 50% clock duty cycle,  $AV_{DD} = 5$  V,  $DRV_{DD} = 3.3$  V, -1 dBFS differential input, and 3 V<sub>PP</sub> differential clock (unless otherwise noted)

PARAMETER			TEST CONDITIONS		TYP	MAX	UNIT
			T <sub>C</sub> = 25°C	75.0	84.0		
		f <sub>IN</sub> = 10 MHz	$T_C = T_{C,MAX}$	74.0			
			$T_C = T_{C,MIN}$	75.0			
		f <sub>IN</sub> = 70 MHz	o o,,		71.8		
			T <sub>C</sub> = 25°C	62.0	67.4		
		f <sub>IN</sub> = 100 MHz	$T_C = T_{C,MAX}$	74.5			
SFDR	Spurious free dynamic range		$T_C = T_{C,MIN}$	63.0			dBc
	, , ,	f <sub>IN</sub> = 170 MHz	T <sub>C</sub> = 25°C	63.0	70.0		
			$T_C = T_{C,MAX}$	65.0			
			$T_C = T_{C,MIN}$	59.0			
		f <sub>IN</sub> = 230 MHz	· C · C,WIIN		74.0		
		f <sub>IN</sub> = 300 MHz			65.8		
		f <sub>IN</sub> = 400 MHz			60.5		
		f <sub>IN</sub> = 10 MHz	T <sub>C</sub> = 25°C	75.0	92.0		
		1  \(\mathbb{A} = 10	$T_C = T_{C,MAX}$	74.0	02.0		
			$T_C = T_{C,MIN}$	76.5			
		f <sub>IN</sub> = 70 MHz	TC = TC,MIN	70.0	71.8		
		$f_{IN} = 100 \text{ MHz}$	T <sub>C</sub> = 25°C	62.0	67.4		
		1 N = 100 WHZ	$T_C = T_{C,MAX}$	76.0	07.4		
HD2	Second harmonic		$T_{C} = T_{C,MIN}$	63.0			dBc
1102	Second Harmonic	f <sub>IN</sub> = 170 MHz	$T_C = 25^{\circ}C$	63.0	73.0		abc
		1 N = 170 WI12	$T_C = T_{C,MAX}$	65.0	75.0		
				59.0			
		f _ 220 MHz	$T_C = T_{C,MIN}$	39.0	74.0		
		f <sub>IN</sub> = 230 MHz			74.0		
		f <sub>IN</sub> = 300 MHz			65.8		
		f <sub>IN</sub> = 400 MHz	T 0500	04.0	60.6		
		f <sub>IN</sub> = 10 MHz	$T_C = 25^{\circ}C$	81.0	84.0		
		. 70 1411	Full temp range	78.5	70.0		
		f <sub>IN</sub> = 70 MHz			72.8		
		f <sub>IN</sub> = 100 MHz	T <sub>C</sub> = 25°C	72.0	78.4		
			$T_C = T_{C,MAX}$	74.5			
HD3	Third harmonic		$T_C = T_{C,MIN}$	65.0			dBc
		f <sub>IN</sub> = 170 MHz	T <sub>C</sub> = 25°C	65.0	70.1		
			$T_C = T_{C,MAX}$	69.0			
			$T_C = T_{C,MIN}$	63.0			
		f <sub>IN</sub> = 230 MHz			94.0		
		f <sub>IN</sub> = 300 MHz			77.7		
		$f_{IN} = 400 \text{ MHz}$			64.1		



# **ELECTRICAL CHARACTERISTICS (continued)**

Typical values at  $T_C = 25$ °C, full temperature range is  $T_{C,MIN} = -55$ °C to  $T_{C,MAX} = 125$ °C, sampling rate = 250 MSPS, 50% clock duty cycle,  $AV_{DD} = 5$  V,  $DRV_{DD} = 3.3$  V, -1 dBFS differential input, and 3 V<sub>PP</sub> differential clock (unless otherwise noted)

	PARAMETER	TES	T CONDITIONS	MIN	TYP MAX	UNIT
			T <sub>C</sub> = 25°C	80.0	89.0	
		f <sub>IN</sub> = 10 MHz	$T_C = T_{C,MAX}$	81.0		
			$T_C = T_{C,MIN}$	75.0		
		f <sub>IN</sub> = 70 MHz			82.7	
		f <sub>IN</sub> = 100 MHz	T <sub>C</sub> = 25°C	74.0	86.6	
			$T_C = T_{C,MAX}$	78.0		
	Worst other harmonic/spur (other		$T_C = T_{C,MIN}$	69.0		dBc
	than HD2 and HD3)	f <sub>IN</sub> = 170 MHz	T <sub>C</sub> = 25°C	70.0	88.2	
			$T_C = T_{C,MAX}$	78.0		
			$T_C = T_{C,MIN}$	64.0		
		f <sub>IN</sub> = 230 MHz	o o,v		81.8	
		f <sub>IN</sub> = 300 MHz			83.6	
		f <sub>IN</sub> = 400 MHz			82.0	
		11.4	T <sub>C</sub> = 25°C	74.5	83.0	
		f <sub>IN</sub> = 10 MHz	$T_C = T_{C,MAX}$	73.0		
	Total harmonic distortion	iiv -	$T_C = T_{C,MIN}$	74.0		
		f <sub>IN</sub> = 70 MHz	· C · C,IMIIN	70	68.9	
		f <sub>IN</sub> = 100 MHz	T <sub>C</sub> = 25°C	61.5	67.0	-
		1  \(\text{IN} = 100 \text{ Wil 12}	$T_C = T_{C,MAX}$	73.0	01.0	
THD .			$T_C = T_{C,MIN}$	60.0		dBc
		f <sub>IN</sub> = 170 MHz	$T_C = 25^{\circ}C$	62.0	68.2	abo
		1 N = 170 WH12	$T_C = T_{C,MAX}$	63.5	00.2	
			$T_C = T_{C,MAX}$ $T_C = T_{C,MIN}$	58.0		
		f <sub>IN</sub> = 230 MHz	IC = IC,MIN	36.0	73.2	
		f <sub>IN</sub> = 300 MHz			65.5	
		f <sub>IN</sub> = 400 MHz	T 05°C	67.7	59.0	
		f 40 MH I-	$T_C = 25^{\circ}C$	67.7	69.2	
		f <sub>IN</sub> = 10 MHz	$T_C = T_{C,MAX}$	66.4		
		. 70.141	$T_C = T_{C,MIN}$	62.9		
		f <sub>IN</sub> = 70 MHz			69.2	
		f <sub>IN</sub> = 100 MHz	T <sub>C</sub> = 25°C	62.2	68.9	
			$T_C = T_{C,MAX}$	66.2		
SINAD	Signal-to-noise and distortion		$T_C = T_{C,MIN}$	59.4		dBc
		f <sub>IN</sub> = 170 MHz	$T_C = 25^{\circ}C$	61.7	68.3	
			$T_C = T_{C,MAX}$	62.9		
			$T_C = T_{C,MIN}$	57.6		
		f <sub>IN</sub> = 230 MHz			67.5	
		f <sub>IN</sub> = 300 MHz			66.6	
		$f_{IN} = 400 \text{ MHz}$			65.4	



## **ELECTRICAL CHARACTERISTICS (continued)**

Typical values at  $T_C = 25$ °C, full temperature range is  $T_{C,MIN} = -55$ °C to  $T_{C,MAX} = 125$ °C, sampling rate = 250 MSPS, 50% clock duty cycle,  $AV_{DD} = 5$  V,  $DRV_{DD} = 3.3$  V, -1 dBFS differential input, and 3  $V_{PP}$  differential clock (unless otherwise noted)

	PARAMETER	TES	TEST CONDITIONS			MAX	UNIT
			T <sub>C</sub> = 25°C	10.9	11.3		Bits
		$f_{IN} = 10 \text{ MHz}$	$T_C = T_{C,MAX}$	10.7			
			$T_C = T_{C,MIN}$	10.1			
			$T_C = 25^{\circ}C$	10.0	11.3		
ENOB	Effective number of bits f	$f_{IN} = 100 \text{ MHz}$	$T_C = T_{C,MAX}$	10.7			
			$T_C = T_{C,MIN}$	9.5			
	f <sub>IN</sub> = 170 MH		T <sub>C</sub> = 25°C	9.9	11.2		
		$f_{IN} = 170 \text{ MHz}$	$T_C = T_{C,MAX}$	10.1			
			$T_C = T_{C,MIN}$	9.2			
	RMS idle channel noise	Inputs tied to commo	on-mode		0.4		LSB
DIGITAL	CHARACTERISTICS – LVDS DI	GITAL OUTPUTS					
Differential output voltage				247		452	mV
	Output offset voltage			1.125	1.25	1.375	V

## **TIMING CHARACTERISTICS**

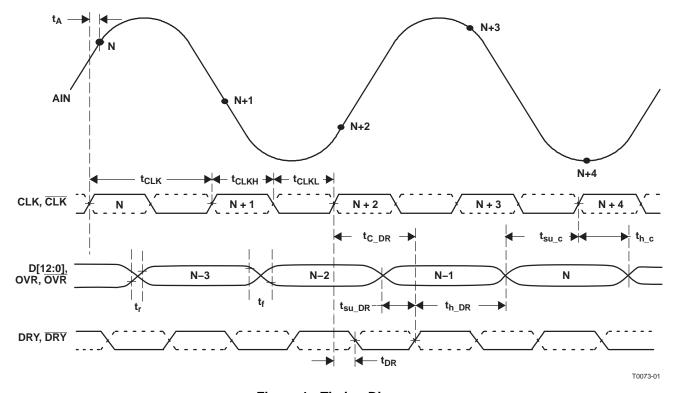


Figure 1. Timing Diagram



#### **TIMING CHARACTERISTICS**

Typical values at  $T_C = 25^{\circ}$ C, 50% clock duty cycle, sampling rate = 250 MSPS,  $AV_{DD} = 5$  V,  $DRV_{DD} = 3.3$  V

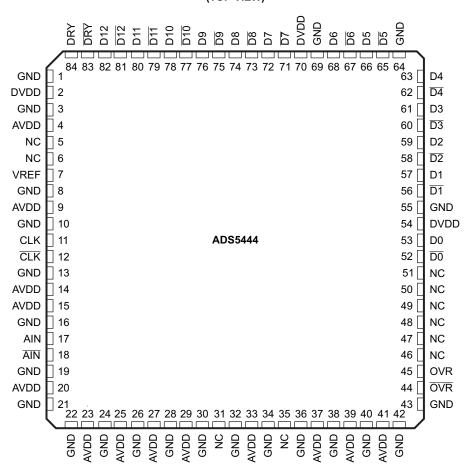
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>A</sub>	Aperture delay			500		ps
tJ	Clock slope independent aperture uncertainty (jitter)			200		fs RMS
	Latency			4		cycles
Clock In	put					
t <sub>CLK</sub>	Clock period			4		ns
t <sub>CLKH</sub>	Clock pulse width high			2		ns
t <sub>CLKL</sub>	Clock pulse width low			2		ns
Clock to	DataReady (DRY)					
t <sub>DR</sub>	Clock rising to DataReady falling			1.1		ns
t <sub>C_DR</sub>	Clock rising to DataReady rising	Clock duty cycle = 50% (1)	2.7	3.1	3.5	ns
Clock to	DATA, OVR <sup>(2)</sup>					
t <sub>r</sub>	Data rise time (20% to 80%)			0.6		ns
t <sub>f</sub>	Data fall time(80% to 20%)			0.6		ns
t <sub>su_c</sub>	Data valid to clock (setup time)			3.1		ns
t <sub>h_c</sub>	Clock to invalid data (hold time)			0.2		ns
	dy (DRY)/DATA, OVR <sup>(2)</sup>					
t <sub>su(DR)</sub>	Data valid to DRY		1.5	2		ns
t <sub>h(DR)</sub>	DRY to invalid data		0.9	1.3		ns

 <sup>(1)</sup> t<sub>C\_DR</sub> = t<sub>DR</sub> + t<sub>CLKH</sub> for clock duty cycles other than 50%
 (2) Data is updated with clock falling edge or DRY rising edge.



## **DEVICE INFORMATION**

# HFG PACKAGE (TOP VIEW)



## **TERMINAL FUNCTIONS**

7	TERMINAL	DECODINE
NAME	NO.	DESCRIPTION
AVDD	4, 9, 14, 15, 20, 23, 25, 27, 29, 33, 37, 39, 41	Analog power supply
DVDD	2, 54, 70	Output driver power supply
GND	1, 3, 8, 10, 13, 16, 19, 21, 22, 24, 26, 28, 30, 32, 34, 36, 38, 40, 42, 43, 55, 64, 69	Ground
VREF	7	Reference voltage
CLK	11	Differential input clock (positive). Conversion initiated on rising edge.
CLK	12	Differential input clock (negative)
AIN	17	Differential input signal (positive)
AIN	18	Differential input signal (negative)
OVR, OVR	44, 45	Over range indicator LVDS output. A logic high signals an analog input in excess of the full-scale range.
D0, <del>D0</del>	52, 53	LVDS digital output pair, least-significant bit (LSB)
D1–D4, <del>D1</del> – <del>D4</del>	56–63	LVDS digital output pairs
D5–D6, <del>D5</del> – <del>D6</del>	65–68	LVDS digital output pairs



### **TERMINAL FUNCTIONS (continued)**

TER	MINAL	DESCRIPTION
NAME	NO.	DESCRIPTION
D7–D11, <del>D7</del> – <del>D11</del>	71–80	LVDS digital output pairs
D12, D12	81, 82	LVDS digital output pair, most-significant bit (MSB)
DRY, DRY	83, 84	Data ready LVDS output pair
NC	5, 6, 31, 35, 46–51	No connect

#### THERMAL CHARACTERISTICS

	PARAMETER	TEST CONDITIONS	TYP	UNIT
$R_{\theta JA}$	Junction-to-free-air thermal resistance	Board mounted, per JESD 51-5 methodology	21.813	°C/W
$R_{\theta JC}$	Junction-to-case thermal resistance	MIL-STD-883 Test Method 1012	0.849	°C/W

#### THERMAL NOTES

This CQFP package has built in vias that electrically and thermally connect the bottom of the die to a pad on the bottom of the package. To efficiently remove heat and provide a low-impedance ground path, a thermal land is required on the surface of the PCB directly underneath the body of the package. During normal surface mount flow solder operations, the heat pad on the underside of the package is soldered to this thermal land creating an efficient thermal path. Normally, the PCB thermal land has a number of thermal vias within it that provide a thermal path to internal copper areas (or to the opposite side of the PCB) that provide for more efficient heat removal. TI typically recommends an 11,9-mm² board-mount thermal pad. This allows maximum area for thermal dissipation, while keeping leads away from the pad area to prevent solder bridging. A sufficient quantity of thermal/electrical vias must be included to keep the device within recommended operating conditions. This pad must be electrically at ground potential.



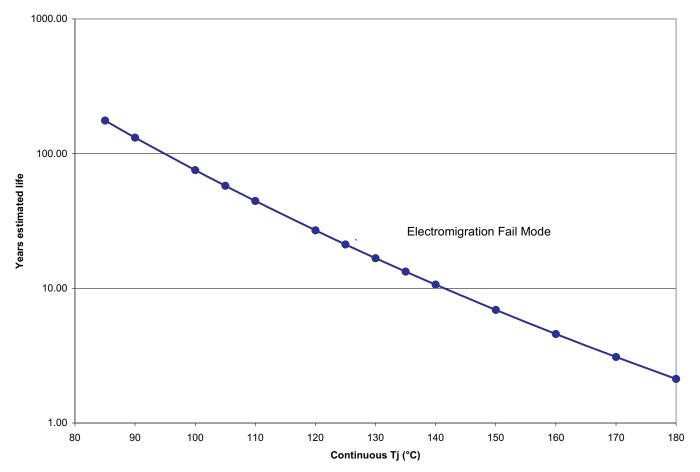


Figure 2. ADS5444 Estimated Device Life at Elevated Temperatures Electromigration Fail Mode **DEFINITION OF SPECIFICATIONS** 

Analog Bandwidth The analog input frequency at which the power of the fundamental is reduced by 3 dB with respect to the low frequency value.

Aperture Delay The delay in time between the rising edge of the input sampling clock and the actual time at which the sampling occurs.

Aperture Uncertainty (Jitter) The sample-to-sample variation in aperture delay.

Clock Pulse Width/Duty Cycle The duty cycle of a clock signal is the ratio of the time the clock signal remains at a logic high (clock pulse width) to the period of the clock signal. Duty cycle is typically expressed as a percentage. A perfect differential sine wave clock results in a 50% duty cycle.

Maximum Conversion Rate The maximum sampling rate at which certified operation is given. All parametric testing is performed at this sampling rate unless otherwise noted.

Minimum Conversion Rate The minimum sampling rate at which the ADC functions.

Differential Nonlinearity (DNL) An ideal ADC exhibits code transitions at analog input values spaced exactly 1 LSB apart. The DNL is the deviation of any single step from this ideal value, measured in units of LSB.

Integral Nonlinearity (INL) The INL is the deviation of the ADCs transfer function from a best fit line determined by a least squares curve fit of that transfer function. The INL at each analog input value is the difference between the actual transfer function and this best fit line, measured in units of LSB.

Gain Error The gain error is the deviation of the ADCs actual input full-scale range from its ideal value. The gain error is given as a percentage of the ideal input full-scale range.



## **DEFINITION OF SPECIFICATIONS (continued)**

Offset Error Offset error is the deviation of output code from mid-code when both inputs are tied to commonmode.

**Temperature Drift** Temperature drift (with respect to gain error and offset error) specifies the change from the value at the nominal temperature to the value at  $T_{MIN}$  or  $T_{MAX}$ . It is computed as the maximum variation the parameters over the whole temperature range divided by  $T_{MIN} - T_{MAX}$ .

**Signal-to-Noise Ratio (SNR)** SNR is the ratio of the power of the fundamental  $(P_S)$  to the noise floor power  $(P_N)$ , excluding the power at dc and the first five harmonics.

$$SNR = 10log_{10} \frac{P_S}{P_N}$$
 (1)

SNR is either given in units of dBc (dB to carrier) when the absolute power of the fundamental is used as the reference, or dBFS (dB to full scale) when the power of the fundamental is extrapolated to the converter's full-scale range.

**Signal-to-Noise and Distortion (SINAD)** SINAD is the ratio of the power of the fundamental ( $P_S$ ) to the power of all the other spectral components including noise ( $P_N$ ) and distortion ( $P_D$ ), but excluding dc.

$$SINAD = 10log_{10} \frac{P_S}{P_N + P_D}$$
 (2)

SINAD is either given in units of dBc (dB to carrier) when the absolute power of the fundamental is used as the reference, or dBFS (dB to full scale) when the power of the fundamental is extrapolated to the converter's full-scale range.

**Effective Resolution Bandwidth** The highest input frequency where the SNR (dB) is dropped by 3 dB for a full-scale input amplitude.

**Total Harmonic Distortion (THD)** THD is the ratio of the power of the fundamental  $(P_S)$  to the power of the first five harmonics  $(P_D)$ .

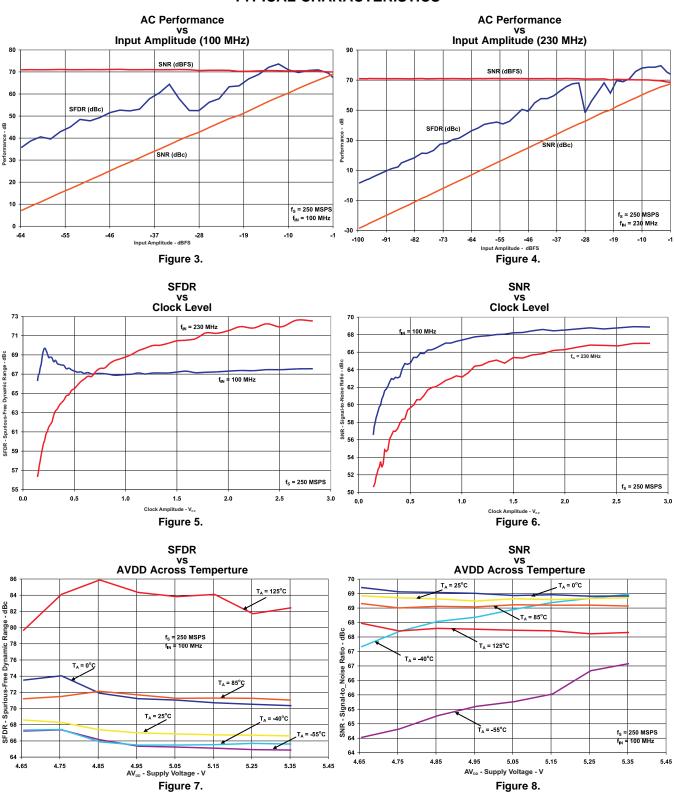
$$THD = 10log_{10} \frac{P_S}{P_D}$$
(3)

THD is typically given in units of dBc (dB to carrier).

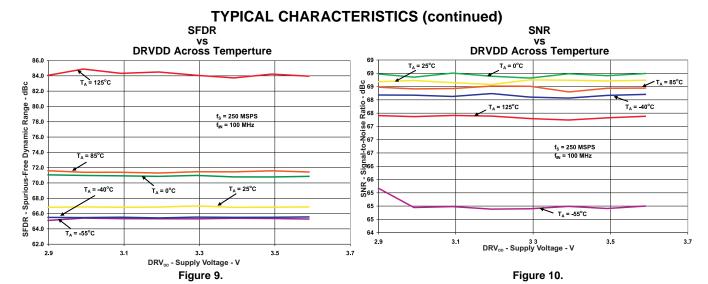
**Two-Tone Intermodulation Distortion** IMD3 is the ratio of the power of the fundamental (at frequencies  $f_1$ ,  $f_2$ ) to the power of the worst spectral component at either frequency  $2f_1 - f_2$  or  $2f_2 - f_1$ ). IMD3 is either given in units of dBc (dB to carrier) when the absolute power of the fundamental is used as the reference or dBFS (dB to full scale) when the power of the fundamental is extrapolated to the converter's full-scale range.



## TYPICAL CHARACTERISTICS







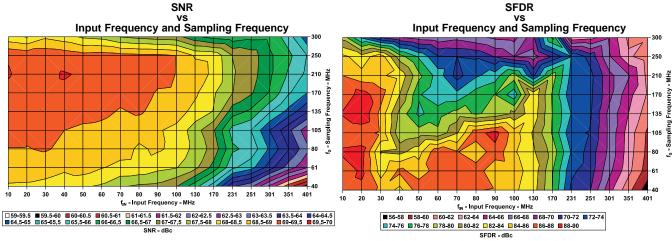


Figure 11. Figure 12.



#### APPLICATION INFORMATION

## **Theory of Operation**

The ADS5444 is a 13 bit, 250 MSPS, monolithic pipeline analog-to-digital converter (ADC). Its bipolar analog core operates from a 5 V supply, while the output uses a 3.3 V supply to provide LVDS compatible outputs. The conversion process is initiated by the rising edge of the external input clock. At that instant, the differential input signal is captured by the input track and hold (T&H) and the input sample is sequentially converted by a series of small resolution stages, with the outputs combined in a digital correction logic block. Both the rising and the falling clock edges are used to propagate the sample through the pipeline every half clock cycle. This process results in a data latency of four clock cycles, after which the output data is available as a 13 bit parallel word, coded in offset binary format.

## **Input Configuration**

The analog input for the ADS5444 consists of an analog differential buffer followed by a bipolar T&H. The analog buffer isolates the source driving the input of the ADC from any internal switching. The input common mode is set internally through a 500  $\Omega$  resistor connected from 2.4 V to each of the inputs. This results in a differential input impedance of 1 k $\Omega$ .

For a full-scale differential input, each of the differential lines of the input signal (pins 17 and 18) swings symmetrically between 2.4 + 0.55 V and 2.4 - 0.55 V. This means that each input has a maximum signal swing of 1.1 V<sub>PP</sub> for a total differential input signal swing of 2.2 V<sub>PP</sub>. The maximum swing is determined by the internal reference voltage generator eliminating the need for any external circuitry for this purpose.

The ADS5444 obtains optimum performance when the analog inputs are driven differentially. The circuit in Figure 13 shows one possible configuration using an RF transformer with termination either on the primary or on the secondary of the transformer. If voltage gain is required, a step up transformer can be used. For voltage gains that would require an impractical transformer turn ratio, a single-ended amplifier driving the transformer is shown in Figure 14.

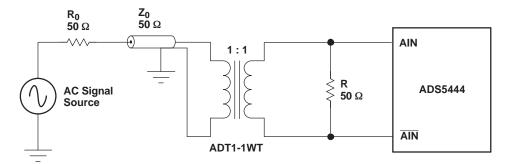


Figure 13. Converting a Single-Ended Input to a Differential Signal Using RF Transformers

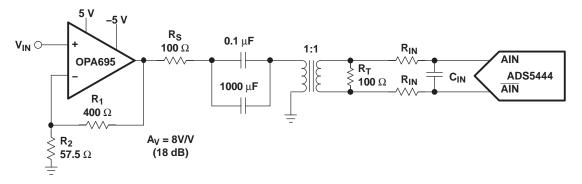


Figure 14. Using the OPA695 with the ADS5444



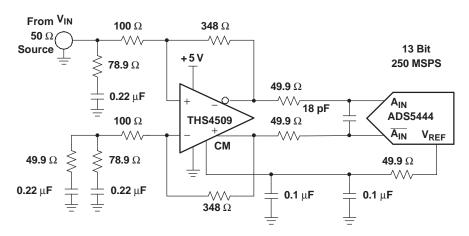


Figure 15. Using the THS4509 with the ADS5444

Besides the OPA695, TI offers a wide selection of single-ended operational amplifiers that can be selected depending on the application. An RF gain block amplifier, such as the TI THS9001, can also be used with an RF transformer for high input frequency applications. For applications requiring dc-coupling with the signal source, a differential input/differential output amplifier like the THS4509 (see Figure 15) is a good solution, as it minimizes board space and reduces the number of components.

In this configuration, the THS4509 amplifier circuit provides 10 dB of gain, converts the single-ended input to differential, and sets the proper input common-mode voltage to the ADS5444.

The 50  $\Omega$  resistors and 18 pF capacitor between the THS4509 outputs and ADS5444 inputs (along with the input capacitance of the ADC) limit the bandwidth of the signal to about 70 MHz (–3 dB).

Input termination is accomplished via the 78.9  $\Omega$  resistor and 0.22  $\mu$ F capacitor to ground in conjunction with the input impedance of the amplifier circuit. A 0.22  $\mu$ F capacitor and 49.9  $\Omega$  resistor are inserted to ground across the 78.9  $\Omega$  resistor and 0.22  $\mu$ F capacitor on the alternate input to balance the circuit.

Gain is a function of the source impedance, termination, and 348  $\Omega$  feedback resistor. See the THS4509 data sheet for further component values to set proper 50  $\Omega$  termination for other common gains.

Because the ADS5444 recommended input common-mode voltage is 2.4 V, the THS4509 is operated from a single power supply input with  $V_{S+} = 5$  V and  $V_{S-} = 0$  V (ground). This maintains maximum headroom on the internal transistors of the THS4509.

## **Clock Inputs**

The ADS5444 clock input can be driven with either a differential clock signal or a single-ended clock input, with little or no difference in performance between both configurations. In low-input frequency applications, where jitter may not be a big concern, the use of single-ended clock (see Figure 16) could save some cost and board space without any trade-off in performance. When driven on this configuration, it is best to connect CLK to ground with a 0.01  $\mu$ F capacitor, while CLK is ac-coupled with a 0.01  $\mu$ F capacitor to the clock source, as shown in Figure 16.

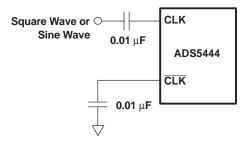


Figure 16. Single-Ended Clock



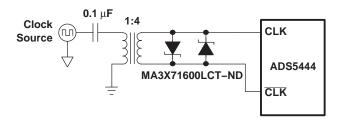


Figure 17. Differential Clock

For jitter-sensitive applications, the use of a differential clock has some advantages (as with any other ADC) at the system level. The first advantage is that it allows for common-mode noise rejection at the PCB level.

A differential clock also allows for the use of bigger clock amplitudes without exceeding the absolute maximum ratings. In the case of a sinusoidal clock, this results in higher slew rates and reduces the impact of clock noise on jitter. See *Clocking High Speed Data Converters* (SLYT075) for more details.

Figure 17 shows this approach. The back-to-back Schottky diodes can be added to limit the clock amplitude in cases where this would exceed the absolute maximum ratings, even when using a differential clock.

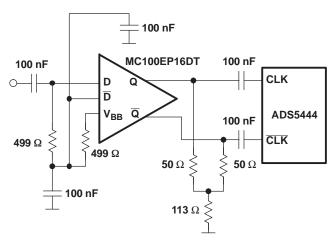


Figure 18. Differential Clock Using PECL Logic

Another possibility is the use of a logic-based clock, such as PECL. In this case, the slew rate of the edges is most likely much higher than the one obtained for the same clock amplitude based on a sinusoidal clock. This solution would minimize the effect of the slope dependent ADC jitter. Using logic gates to square a sinusoidal clock may not produce the best results, as logic gates may not have been optimized to act as comparators, adding too much jitter while squaring the inputs.

The common-mode voltage of the clock inputs is set internally to 2.4 V using internal 1 k $\Omega$  resistors. It is recommended to use ac coupling, but if this scheme is not possible due to, for instance, asynchronous clocking, the ADS5444 features good tolerance to clock common-mode variation.

Additionally, the internal ADC core uses both edges of the clock for the conversion process. Ideally, a 50% duty cycle clock signal should be provided.

## **Digital Outputs**

The ADC provides 13 data outputs (D12 to D0, with D12 being the MSB and D0 the LSB), a data-ready signal (DRY), and an over-range indicator (OVR) that equals a logic high when the output reaches the full-scale limits. The output format is offset binary. It is recommended to use the DRY signal to capture the output data of the ADS5444.

The ADS5444 digital outputs are LVDS compatible.



## **Power Supplies**

The use of low-noise power supplies with adequate decoupling is recommended. Linear supplies are the preferred choice versus switched ones, which tend to generate more noise components that can be coupled to the ADS5444.

The ADS5444 uses two power supplies. For the analog portion of the design, a 5 V AVDD is used, while for the digital outputs supply (DRVDD) TI recommends the use of 3.3 V. All the ground pins are marked as GND, although AGND pins and DRGND pins are not tied together inside the package.

## **Layout Information**

The evaluation board represents a good guideline of how to lay out the board to obtain the maximum performance out of the ADS5444. General design rules such as the use of multilayer boards, single ground plane for ADC ground connections and local decoupling ceramic chip capacitors should be applied. The input traces should be isolated from any external source of interference or noise including the digital outputs, as well as the clock traces. The clock signal traces should also be isolated from other signals, especially in applications where low jitter is required as high IF sampling.

Besides performance-oriented rules, care has to be taken when considering the heat dissipation out of the device.

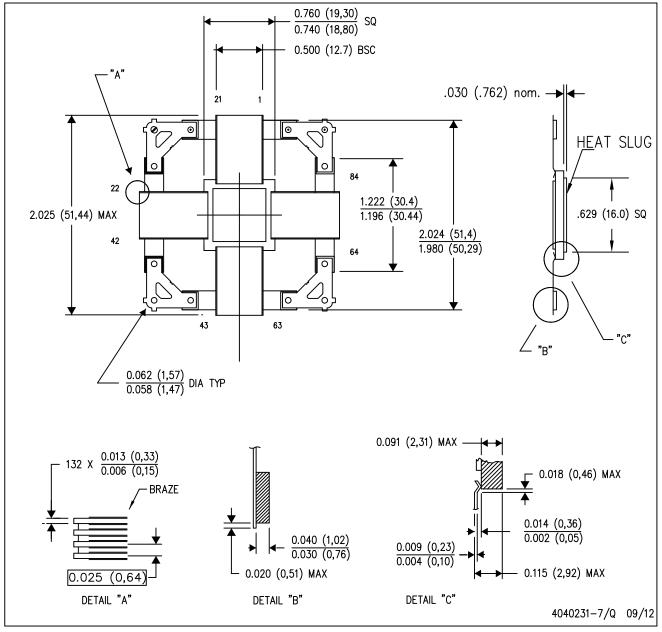


## **REVISION HISTORY**

Cł	hanges from Revision B (February 2012) to Revision C	Page
•	Added /EM bullet to FEATURES	
•	Deleted ORDERING INFORMATION table	

# HFG (S-CQFP-F84)

# CERAMIC QUAD FLATPACK WITH NCTB



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Ceramic quad flatpack with flat leads brazed to non-conductive tie bar carrier.
- D. This package is hermetically sealed with a metal lid.
- E. The leads are gold plated and can be solderdipped.
- F. Leads not shown for clarity purposes.



www.ti.com

10-Nov-2025

#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
5962-0720701VXC	Active	Production	CFP (HFG)   84	1   OTHER	ROHS Exempt	Call TI	N/A for Pkg Type	-55 to 125	5962- 0720701VXC ADS5444MHFG-V
ADS5444HFG/EM	Active	Production	CFP (HFG)   84	1   OTHER	ROHS Exempt	Call TI	N/A for Pkg Type	25 to 25	ADS5444HFG/EM EVAL ONLY

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF ADS5444-SP:

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

## PACKAGE OPTION ADDENDUM

www.ti.com 10-Nov-2025

● Catalog : ADS5444

● Enhanced Product : ADS5444-EP

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

## IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale, TI's General Quality Guidelines, or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2025, Texas Instruments Incorporated

Last updated 10/2025